


<b>Search Notes</b>  	<b>Application/Control No.</b>  10597135	<b>Applicant(s)/Patent Under Reexamination</b>  HUECK ET AL.
	<b>Examiner</b>  WEI ZHAO	<b>Art Unit</b>  2419

SEARCHED			
Class	Subclass	Date	Examiner
370	232	6/8	WZ
709	223	6/8	WZ

SEARCH NOTES		
Search Notes	Date	Examiner
Searched using US-PGPUB, USPAT, DERWENT, IBM_TDB in EAST	6/8	WZ
Did double patenting search; did inventorship search for ODP in Palm Resource Center	6/8	WZ

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
370	232	6/8	WZ

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